
Digitalne izboljšane brezvrvišne telekomunikacije (DECT) - Digitalno omrežje z integriranimi storitvami (ISDN) - Vzajemno delovanje DECT/ISDN v obliki posredovalnega sistema - 2. del: Preskuševalna specifikacija, odvisna od profila (PSTS), za prenosno radijsko zaključitev (PT)

Digital Enhanced Cordless Telecommunications (DECT); Integrated Services Digital Network (ISDN); DECT/ISDN interworking for intermediate system configuration; Part 2: Profile Specific Test Specification (PSTS) for Portable radio Termination (PT)

Ta slovenski standard je istoveten z: EN 301 614-2 V1.1.2:1999-02

ICS:

33.070.30	Digitalne izboljšane brezvrvišne telekomunikacije (DECT)	Digital Enhanced Cordless Telecommunications (DECT)
33.080	Digitalno omrežje z integriranimi storitvami (ISDN)	Integrated Services Digital Network (ISDN)

PSIST EN 301 614-2:1999

en

EN 301 614-2 V1.1.2 (1999-02)

European Standard (Telecommunications series)

**Digital Enhanced Cordless Telecommunications (DECT);
Integrated Services Digital Network (ISDN);
DECT/ISDN interworking for
intermediate system configuration;
Part 2: Profile Specific Test Specification (PSTS) for
Portable radio Termination (PT)**



Reference

DEN/DECT-040104-2 (ey0i0idc.PDF)

Keywords

DECT, ICS, ISDN, profile

ETSI

Postal address

F-06921 Sophia Antipolis Cedex - FRANCE

Office address

650 Route des Lucioles - Sophia Antipolis
Valbonne - FRANCE
Tel.: +33 4 92 94 42 00 Fax: +33 4 93 65 47 16
Siret N° 348 623 562 00017 - NAF 742 C
Association à but non lucratif enregistrée à la
Sous-Préfecture de Grasse (06) N° 7803/88

Internet

secretariat@etsi.fr
Individual copies of this ETSI deliverable
can be downloaded from
<http://www.etsi.org>
If you find errors in the present document, send your
comment to: editor@etsi.fr

Copyright Notification

No part may be reproduced except as authorized by written permission.
The copyright and the foregoing restriction extend to reproduction in all media.

© European Telecommunications Standards Institute 1999.
All rights reserved.

Contents

Intellectual Property Rights.....	7
Foreword	7
1 Scope	8
2 Normative references	8
3 Definitions and abbreviations	11
3.1 Definitions	11
3.2 Abbreviations.....	11
4 DECT NWK layer protocol	12
4.1 Additional Test Purposes (TPs)	12
4.1.1 Additional TPs for IIP CC specific behaviours	13
4.1.1.1 Test group PT/CC/BV/IS	13
4.1.1.2 Test group PT/CC/BI/IS	13
4.1.1.3 Test group PT/CC/BO/IS	14
4.1.1.4 Test group PT/CC/BI/IS	14
4.1.2 Additional TPs for IIP LCE specific behaviours.....	14
4.1.2.1 Test group PT/LC/BV/IS.....	14
4.2 Abstract Test Method (ATM).....	14
4.3 Relevant test cases	14
4.4 Additional test cases	16
4.5 Modified test cases.....	16
5 DECT Data Link Control layer (DLC) layer protocol.....	17
5.1 Additional TPs	17
5.1.1 Additional TPs for C-plane class B procedures	19
5.1.1.1 Test group CA	19
5.1.1.2 Test group BV	21
5.1.1.3 Test group BI.....	22
5.1.1.4 Test group BO	23
5.1.2 Additional TPs for U-plane LU7 procedures	24
5.1.2.1 Test group BV	24
5.1.3 Additional TPs for U-plane LU8 procedures	24
5.1.3.1 Test group BV	24
5.2 ATM	25
5.3 Relevant test cases	25
5.4 Additional test cases	25
5.4.1 Additional test cases for C-plane class B	25
5.4.2 Additional test cases for U-plane LU7	25
5.4.3 Additional test cases for U-plane LU8	25
5.5 Modified test cases.....	25
6 DECT MAC layer protocol.....	26
6.1 Additional TPs	26
6.1.1 Additional TPs for advanced symmetric connections	27
6.1.2 Additional TPs for C-plane switching procedures.....	27
6.1.2.1 Dynamic switching C_F to C_S : DIFS initiated	27
6.1.2.2 Dynamic switching C_S to C_F : DIFS initiated.....	28
6.1.2.3 Dynamic switching C_S to C_F : DIFS initiated.....	28
6.1.2.4 Dynamic switching C_{Sx} to C_{Sy} : DIFS initiated	29
6.1.3 Additional TPs for U-plane switching procedures	29
6.1.3.1 Connection handover procedure	29
6.1.3.2 Release of part of double slot procedure	30
6.2 ATM	30
6.3 Relevant test cases	30
6.4 Additional test cases	31

6.4.1	Additional test cases for advanced symmetric connections	31
6.4.2	Additional test cases for C-plane switching procedures	31
6.4.3	Additional test cases for U-plane switching procedures	31
6.5	Modified test cases.....	32
7	DECT PHL protocol	32
7.1	Additional TPs	32
7.2	ATM	32
7.3	Relevant test cases	32
7.4	Additional test cases	32
7.5	Modified test cases.....	32
8	ISDN basic access protocols	33
8.1	Applicability of ATS.....	33
8.2	Additional TPs	33
8.3	ATM	33
8.4	Relevant test cases	33
9	DECT/ISDN IIP profile	34
9.1	Profile TSS	34
9.1.1	Test groups	34
9.1.1.1	Functional modules.....	34
9.1.1.2	Main test groups	34
9.1.1.2.1	Capability (CA) tests.....	34
9.1.1.2.2	BV tests.....	35
9.1.1.2.3	BO tests.....	35
9.1.1.2.4	BI tests	35
9.2	Profile TPs	35
9.2.1	TP definition conventions	35
9.2.2	TP naming conventions	36
9.2.3	Sources of TP definitions	36
9.2.4	TPs for IWU Link Association Entity	37
9.2.5	TPs for IWU missing resource management	37
9.2.6	TPs for IWU Call Control specific procedures	38
9.3	Profile ATM	38
9.4	Profile untestable TPs	39
9.5	Profile ATS conventions.....	40
9.5.1	Declarations part naming conventions.....	40
9.5.1.1	Type and structured type definitions.....	40
9.5.1.2	Operations definitions.....	40
9.5.1.3	Parameter declarations.....	40
9.5.1.4	Selection expression definitions	40
9.5.1.5	Constant declarations.....	40
9.5.1.6	Test suite variable declarations.....	41
9.5.1.7	Test case variable declarations	41
9.5.1.8	PCO declarations	41
9.5.1.9	Timer declarations	41
9.5.1.10	ASP type definitions	41
9.5.1.11	PDU type definitions	42
9.5.1.12	Alias definitions.....	42
9.5.2	Constraints part naming conventions.....	42
9.5.3	Dynamic part naming conventions	42
9.5.3.1	Test Case identifier.....	43
9.5.3.2	Test Step identifier	43
9.5.3.3	Default identifier.....	43
9.5.3.4	General aspects	43
9.5.3.5	ATS abbreviations	44
9.5.4	Declaration part implementation conventions	44
9.5.5	Constraint part implementation conventions	44
9.5.6	Dynamic part implementation conventions	45
9.5.7	Documentation implementation conventions	45

9.6	Test case and TP mapping	46
Annex A (normative):	Profile IXIT proforma	47
A.1	Identification summary	47
A.2	ATS summary	47
A.3	Test laboratory	47
A.4	Client identification	48
A.5	System Under Test (SUT).....	48
A.6	Profile information.....	49
A.6.1	NWK layer.....	49
A.6.2	DLC layer	51
A.6.3	MAC layer	53
Annex B (normative):	Profile Conformance Test Report (Profile CTR) proforma	55
B.1	Identification summary	55
B.1.1	Protocol conformance test report	55
B.1.2	IUT identification	55
B.1.3	Testing environment	56
B.1.4	Limits and reservation.....	56
B.1.5	Comments	56
B.2	IUT conformance status	56
B.3	Static conformance summary	57
B.4	Dynamic conformance summary.....	57
B.5	Static conformance review report	57
B.6	Test campaign report.....	58
B.7	Observations.....	58
Annex C (normative):	System Conformance Test Report (SCTR) proforma	59
C.1	Identification summary	59
C.1.1	System conformance test report	59
C.1.2	Test laboratory	59
C.1.3	Client identification	60
C.1.4	SUT.....	60
C.1.5	Profile identification	60
C.1.6	Nature of conformance testing	61
C.1.7	Limits and reservations	61
C.1.8	Record of agreement	61
C.1.9	Comments	62
C.2	System report summary for DECT/ISDN IIP PT.....	62
C.2.1	Profile testing summary for DECT NWK layer protocol.....	62
C.2.2	Profile testing summary for DECT DLC layer protocol	63
C.2.3	Profile testing summary for DECT MAC layer protocol	64
C.2.4	Profile testing summary for DECT PHL protocol.....	65
C.2.5	Profile testing summary for ISDN L2, L1 basic access protocol	66
C.2.6	Profile testing summary for DECT/ISDN IIP Profile	67
Annex D (normative):	Profile IXIT Requirements List (XRL) proforma	68
D.1	Profile eXtra Requirement List for IIP - PT part	68
D.1.1	Parameters for IWU layer	68
D.1.2	Specific parameters for NWK layer.....	68
D.1.3	Specific parameters for DLC layer	69

D.1.4	Specific parameters for MAC layer	69
Annex E (normative):	Modifications of DECT Common Interface (CI) PCTR proforma	70
E.1	Modifications of DECT NWK layer PCTR proforma	70
E.2	Modifications of DECT DLC layer PCTR proforma	73
E.3	Modifications of DECT MAC layer PCTR proforma	76
E.4	Observations	77
Annex F (normative):	Abstract Test Suite (ATS) - NWK layer	78
F.1	The TTCN Graphical form (TTCN.GR)	78
F.2	The TTCN Machine Processable form (TTCN.MP)	78
Annex G (normative):	Abstract Test Suite (ATS) - DLC layer	79
G.1	The TTCN Graphical form (TTCN.GR)	79
G.2	The TTCN Machine Processable form (TTCN.MP)	79
Annex H (normative):	Abstract Test Suite (ATS) - MAC layer	80
H.1	The TTCN Graphical form (TTCN.GR)	80
H.2	The TTCN Machine Processable form (TTCN.MP)	80
Annex J (normative):	Abstract Test Suite (ATS) - Interworking Unit (IWU)	81
J.1	The TTCN Graphical form (TTCN.GR)	81
J.2	The TTCN Machine Processable form (TTCN.MP)	81
History		82